

Publications/Services Standards Conferences Careers/Jobs

Welcome **United States Patent and Trademark Office**



Help

Terms

IEEE Peer Review Quick Links

Welcome to IEEE Xplore®

()- Home

)- What Can I Access?

C Log-out

Tables of Contents

()- Journals & Magazines

)- Conference **Proceedings**

()- Standards

Search

O- By Author

- Basic

Advanced

Member Services

O- Join IEEE

)- Establish IEEE Web Account

O- Access the **IEEE Member** Digital Library Your search matched 3 of 1022101 documents.

A maximum of 500 results are displayed, 15 to a page, sorted by Relevance Descending order.

Refine This Search:

You may refine your search by editing the current search expression or enterior new one in the text box.

((degree <or> extent <or> limit* <or> threshold* <or



□ Check to search within this result set

Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

1 Capacity of text marking channel

Low, S.H.; Maxemchuk, N.F.;

Signal Processing Letters, IEEE , Volume: 7 , Issue: 12 , Dec. 2000

Pages: 345 - 347

[Abstract] [PDF Full-Text (56 KB)]

2 A robust oblivious watermarking scheme

Ramkumar, M.; Akansu, A.N.;

Image Processing, 2000. Proceedings. 2000 International Conference on , Vo 2 , 10-13 Sept. 2000

Pages: 61 - 64 vol. 2

[Abstract] [PDF Full-Text (352 KB)]

3 Image watermarking with zero-mean patches

Ratnakar, V.;

Signals, Systems, and Computers, 1999. Conference Record of the Thirty-Thi Asilomar Conference on , Volume: 2 , 24-27 Oct. 1999

Pages:1513 - 1517 vol.2

[Abstract] [PDF Full-Text (560 KB)]

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

Copyright @ 2004 IEEE - All rights reserved



Membership Publicat	ions/Services Standards Conferences Careers/Jobs
IEEE X	
	EE Peer Review Quick Links » S
Welcome to IEEE Xplore® - Home - What Can I Access?	Your search matched 45 documents.
C- Log-out Tables of Contents	A maximum of 500 results are displayed, 15 to a page, sorted by Relevanc Descending order.
O- Journals & Magazines	Results Key: JNL = Journal or Magazine CNF = Conference STD = Standard
Conference Proceedings Standards	1 The Frequency Spectrum of Electrical Sliding Contact Noise and Its Waveform Model Taniguchi, M.; Inoue, T.; Mano, K.; Components, Hybrids, and Manufacturing Technology, IEEE Transactions on
Search O- By Author O- Basic O- Advanced	also IEEE Trans. on Components, Packaging, and Manufacturing Technology, A, B, C] ,Volume: 8 , Issue: 3 , Sep 1985 Pages:366 - 371
	[Abstract] [PDF Full-Text (640KB)] IEEE JNL
Member Services - Join IEEE - Establish IEEE - Web Account	2 Fully boosted 64K dynamic RAM with automatic and self-refresh Taniguchi, M.; Yoshihara, T.; Yamada, M.; Shimotori, K.; Nakano, T.; Gamou Solid-State Circuits, IEEE Journal of ,Volume: 16 , Issue: 5 , Oct 1981 Pages:492 - 498
O- Access the IEEE Member	[Abstract] [PDF Full-Text (1184KB)] IEEE JNL
Digital Library	3 A 500-MHz pipelined burst SRAM with improved SER immunity Sato, H.; Wada, T.; Ohbayashi, S.; Kozaru, K.; Okamoto, Y.; Higashide, Y.; Shimizu, T.; Maki, Y.; Morimoto, R.; Otoi, H.; Koga, T.; Honda, H.; Taniguch Arita, Y.; Shiomi, T.; Solid-State Circuits, IEEE Journal of ,Volume: 34 , Issue: 11 , Nov. 1999 Pages:1571 - 1579
	[Abstract] [PDF Full-Text (548KB)] IEEE JNL
	A 5-MHz, 3.6-mW, 1.4-V SRAM with nonboosted, vertical bipolar bi contact memory cell Sato, H.; Nagaoka, H.; Honda, H.; Maki, Y.; Wada, T.; Arita, Y.; Tsutsumi, K Taniguchi, M.; Yamada, M.; Solid-State Circuits, IEEE Journal of ,Volume: 33 , Issue: 11 , Nov. 1998 Pages:1672 - 1681

5 Basic study on the application of parametric spline functions to the

[Abstract] [PDF Full-Text (220KB)] IEEE JNL

holographic pattern measuring system

Taniguchi, M.; Tsuchiya, T.; Takagi, T.;

Instrumentation and Measurement, IEEE Transactions on ,Volume: 47 , Issue

1, Feb. 1998 Pages: 153 - 157

[Abstract] [PDF Full-Text (148KB)] IEEE JNL

6 Holographic pattern measuring system and its application to deformation analysis of printed circuit board due to heat of mounted

Taniguchi, M.; Takagi, T.;

Instrumentation and Measurement, IEEE Transactions on ,Volume: 43, Issue 2 , Apr 1994

Pages: 326 - 331

[Abstract] [PDF Full-Text (596KB)] IEEE JNL

7 The feature of the narrow-pulse transmission on conventional copli waveguides when power leakage is present

Tsuji, M.; Taniguchi, M.; Shigesawa, H.;

Microwave Theory and Techniques, IEEE Transactions on ,Volume: 41 , Issue

6 , June-July 1993 Pages:1017 - 1023

[Abstract] [PDF Full-Text (660KB)] IEEE JNL

8 A holographic measurement of microscopical sliding of electrical co due to contact spring thermal deformation

Taniguchi, M.; Sone, H.; Takagi, T.;

Components, Hybrids, and Manufacturing Technology, IEEE Transactions on [also IEEE Trans. on Components, Packaging, and Manufacturing Technology, A, B, C] ,Volume: 13 , Issue: 1 , March 1990 Pages: 20 - 26

[Abstract] [PDF Full-Text (700KB)] IEEE JNL

9 Videotex: advancing to higher bandwidth

Sugimoto, M.; Taniguchi, M.; Yokoi, S.; Hata, H.;

Communications Magazine, IEEE ,Volume: 26 , Issue: 2 , Feb. 1988

Pages: 22 - 30

[Abstract] [PDF Full-Text (676KB)] IEEE JNL

10 Physiological, clinical and psychological applications of dynamic infrared imaging

Anbar, M.;

Engineering in Medicine and Biology Society, 2003. Proceedings of the 25th A International Conference of the IEEE , Volume: 2, 17-21 Sept. 2003 Pages:1121 - 1124

[Abstract] [PDF Full-Text (370KB)] IEEE CNF

11 An effective electrical isolation scheme by iron implantation at diff

substrate temperatures

Too, P.; Ahmed, S.; Sealy, B.J.; Gwilliam, R.; Ion Implantation Technology. 2002. Proceedings of the 14th International Conference on , 22-27 Sept. 2002 Pages:610 - 613

[Abstract] [PDF Full-Text (324KB)] IEEE CNF

12 An experimental study on the relationships between the speckle n and the deformation of optical fiber

Taniguchi, M.; Hasegawa, M.; Takagi, T.;

SICE 2002. Proceedings of the 41st SICE Annual Conference , Volume: 5 , 5-2002

Pages: 2967 - 2971 vol.5

[Abstract] [PDF Full-Text (352KB)] IEEE CNF

13 A theoretical approach to analysis on the downstream and upstrea road traffic flow rate of a single intersection

Takagi, T.; Taniguchi, M.; Fujiki, S.; Kamimura, S.; Suzuki, N.;

SICE 2002. Proceedings of the 41st SICE Annual Conference , Volume: 5 , 5-2002

Pages: 2873 - 2878 vol. 5

[Abstract] [PDF Full-Text (306KB)] IEEE CNF

14 Application of holographic interferometry measuring technique to deformation measurement of bone due to thermal stress

Kozuchi, J.; Taniguchi, M.; Chubachi, N.; Takaqi, T.;

Instrumentation and Measurement Technology Conference, 2002. IMTC/2002 Proceedings of the 19th IEEE ,Volume: 1 , 21-23 May 2002 Pages: 369 - 374 vol.1

[Abstract] [PDF Full-Text (853KB)] IEEE CNF

15 Fabrication of flat electrodes with nano-gaps using cluster ion bea Taniguchi, M.; Kawai, T.; Watanabe, K.; Matsui, S.; Toyoda, N.; Yamada, I.; Kubota, T.; Mashik, S.;

Microprocesses and Nanotechnology Conference, 2002. Digest of Papers. Microprocesses and Nanotechnology 2002. 2002 International, 6-8 Nov. 200. Pages: 152 - 153

[Abstract] [PDF Full-Text (171KB)] IEEE CNF

1 2 3 Next

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

Copyright © 2004 IEEE - All rights reserved

O- Join IEEE

C Access the **IEEE Member**

C Establish IEEE Web Account

Digital Library

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Mem	bership	Publ	ications/Services	Standards	Conferences	Careers/Jobs
			Xplore RELEASE 1.6		United States Pa	Welcome Itent and Traden
Help	FAQ	Terms	IEEE Peer Review	Quick Lin	nks	abla



Welcome tes Patent and Trademark Office » S€ \triangle Welcome to IEEE Xplore® C Home Your search matched 45 documents. — What Can I Access? A maximum of 500 results are displayed, 15 to a page, sorted by Relevance ()- Log-out **Descending** order. **Tables of Contents Results Key:** — Journals JNL = Journal or Magazine CNF = Conference STD = Standard & Magazines > Conference 16 Application of digital still camera to improve the extracting proces **Proceedings** holographic vibration fringe pattern from interferogram Standards Taniguchi, M.; Takagi, T.; Instrumentation and Measurement Technology Conference, 2001. IMTC 2001 Search Proceedings of the 18th IEEE ,Volume: 2 , 21-23 May 2001 O- By Author Pages: 1060 - 1064 vol. 2 C Basic [Abstract] [PDF Full-Text (772KB)] IEEE CNF C - Advanced 17 Study of field emission characteristics and surface compositions of **Member Services** carbon and silicon emitters utilizing scanning atom probe

Nishikawa, O.; Yagyu, T.; Watanabe, M.; Taniguchi, M.; Murakami, T.; Kondc Vacuum Microelectronics Conference, 2001. IVMC 2001. Proceedings of the 1 International, 12-16 Aug. 2001

Pages: 251 - 252

[Abstract] [PDF Full-Text (152KB)] IEEE CNF

18 Failure diagnosis method for machinery in unsteady operating condition by instantaneous power spectrum and genetic programming

Peng Chen; Toyota, T.; Taniguchi, M.; Fang Feng; Hiho, T.;

Knowledge-Based Intelligent Engineering Systems and Allied Technologies, 20 Proceedings. Fourth International Conference on ,Volume: 2 , 30 Aug.-1 Sep 2000

Pages:640 - 643 vol.2

[Abstract] [PDF Full-Text (272KB)] IEEE CNF

19 Extraction of feature spectra by instantaneous power spectrum an automatic generation of symptom parameters by GP for diagnosis of machinery in unsteady operating condition

Taniguchi, M.; Peng Chen; Toyota, T.;

Industrial Electronics Society, 2000. IECON 2000. 26th Annual Confjerence of

IEEE ,Volume: 3 , 22-28 Oct. 2000

Pages:1696 - 1700 vol.3



Publications/Services Standards Conferences Welcome **United States Patent and Trademark Office** » S€ IEEE Peer Review Quick Links Help Terms Welcome to IEEE Xplore® O- Home Your search matched 45 documents. O- What Can I Access? A maximum of 500 results are displayed, 15 to a page, sorted by Relevance C Log-out **Descending** order. **Tables of Contents Results Key:** O- Journals **JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard & Magazines C Conference 31 Industrial applications of short-term prediction on chaotic time se **Proceedings** by local fuzzy reconstruction method Standards Iokibe, T.; Koyama, M.; Taniguchi, M.; Knowledge-Based Intelligent Electronic Systems, 1997. KES '97. Proceedings. Search 1997 First International Conference on ,Volume: 1 , 21-23 May 1997 O- By Author Pages:126 - 130 vol.1 O- Basic [Abstract] [PDF Full-Text (428KB)] IEEE CNF Advanced 32 Optical adaptive processing for an intensity invariant pattern **Member Services** recognition O- Join IEEE Matsuoka, K.; Taniguchi, M.; Mokuno, Y.; Lasers and Electro-Optics, 1995. Technical Digest. CLEO/Pacific Rim'95., Pacif)— Establish IEEE Web Account Rim Conference on , 10-14 July 1995 Pages:290 O- Access the **IEEE Member** [Abstract] [PDF Full-Text (132KB)] IEEE CNF Digital Library 33 Use of limited distortion invariant correlation filters for recognition road signs Taniguchi, M.; Matsuoka, K.; Lasers and Electro-Optics, 1995. Technical Digest. CLEO/Pacific Rim'95., Pacil Rim Conference on , 10-14 July 1995 Pages:290 [Abstract] [PDF Full-Text (240KB)] IEEE CNF 34 A new structure of field emitter arrays Itoh, S.; Niiyama, T.; Taniguchi, M.; Watanabe, T.; Vacuum Microelectronics Conference, 1995. IVMC., 1995 International, 30 Ju Aug. 1995 Pages:99 - 102

35 Thermal deformation measurement and evaluation of printed circu

[Abstract] [PDF Full-Text (224KB)] IEEE CNF

board by using holography

Taniguchi, M.; Takagi, T.;

Instrumentation and Measurement Technology Conference, 1994. IMTC/94. Conference Proceedings. 10th Anniversary. Advanced Technologies in I & M., IEEE , 10-12 May 1994

Pages:1527 - 1528 vol.3

[Abstract] [PDF Full-Text (168KB)] IEEE CNF

36 An experimental study on the application of stroboscopic holograp impulsive vibration analysis of printed circuit board

Taniguchi, M.; Takagi, T.; Akasaki, I.;

Instrumentation and Measurement Technology Conference, 1994. IMTC/94. Conference Proceedings. 10th Anniversary. Advanced Technologies in I & M., IEEE , 10-12 May 1994

Pages: 204 - 207 vol.1

[Abstract] [PDF Full-Text (356KB)] IEEE CNF

37 A study on efficiency of the driver information system in the Tokyc Metropolitan area

Hato, E.; Taniguchi, M.;

Vehicle Navigation and Information Systems Conference, 1994. Proceedings., 1994, 31 Aug.-2 Sept. 1994

Pages:401 - 404

[Abstract] [PDF Full-Text (244KB)] IEEE CNF

38 Comparison Of Different Neural Approximation Approaches In The **Tracking Problem**

Taniguchi, M.; Lang, M.;

Neural Networks, 1993. IJCNN '93-Nagoya. Proceedings of 1993 Internationa Conference on ,Volume: 2 , October 25-29, 1993

Pages:1743 - 1746

[Abstract] [PDF Full-Text (348KB)] IEEE CNF

39 Driving control system for an autonomous vehicle using multiple observed point information

Hattori, A.; Hosaka, A.; Taniguchi, M.; Nakano, E.;

Intelligent Vehicles '92 Symposium., Proceedings of the , 29 June-1 July 1992 Pages: 207 - 212

[Abstract] [PDF Full-Text (488KB)] IEEE CNF

40 Basic study on possibility for application of optical fiber to the interferometry

Taniguchi, M.; Oki, M.; Takagi, T.;

Instrumentation and Measurement Technology Conference, 1991. IMTC-91. Conference Record., 8th IEEE, 14-16 May 1991

Pages:135 - 137

[Abstract] [PDF Full-Text (252KB)] IEEE CNF

41 Enhanced reliability of HEMT by using a TiN barrier

Taniguchi, M.; Amano, Y.; Nemoto, T.; Shinohara, K.; Reliability Physics Symposium, 1990. 28th Annual Proceedings., International 29 March 1990 Pages: 94 - 98

[Abstract] [PDF Full-Text (252KB)] IEEE CNF

42 A holographic measurement of microscopical sliding of electrical contact due to contact spring thermal deformation

Taniguchi, M.; Sone, H.; Takagi, T.; Electrical Contacts, 1989., Proceedings of the Thirty Fifth Meeting of the IEEE Conference on , 18-20 Sept. 1989

Pages: 245 - 252

[Abstract] [PDF Full-Text (824KB)] IEEE CNF

43 Holographic pattern testing of printed circuit board (PCB) deforma due to thermal stress

Taniguchi, M.; Takagi, T.; Electronic Manufacturing Technology Symposium, 1989, Proceedings. Japan I Symposium, Sixth IEEE/CHMT International, 26-28 April 1989 Pages: 272 - 275

[Abstract] [PDF Full-Text (412KB)] IEEE CNF

44 A Holographic Pattern Measuring System (HPMS) and Its Applicati the Thermal Deformation of an Electrical Contact Spring

Taniguchi, M.; Oki, M.; Takagi, T.;

Precision Electromagnetic Measurements, 1988. CPEM 88 Digest. 1988 Confe on , June 7-10, 1988

Pages: 357 - 357

[Abstract] [PDF Full-Text (356KB)] IEEE CNF

45 Broadcast camera using digital signal processing

Asada, R.; Nishikawa, S.; Toyoda, H.; Miyakawa, Y.; Kitamura, Y.; Watanabe Kiguchi, T.; Taniguchi, M.;

Broadcasting Convention, 1990. IBC 1990., International, 21-25 Sep 1990 Pages: 159 - 163

[Abstract] [PDF Full-Text (264KB)] IEE CNF

Prev 1 2 3

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

Copyright © 2004 IEEE - All rights reserved

Membership Publications/Services Standards Conferences Careers/Jobs



IEEE)	Welcome United States Patent and Trademark Office Welcome United States Patent and Trademark Office
Help FAQ Terms I	IEEE Peer Review Quick Links St
Welcome to IEEE Xplore* - Home - What Can	Your search matched 1 documents.
I Access? — Log-out	A maximum of 500 results are displayed, 15 to a page, sorted by Relevanc Descending order.
Tables of Contents - Journals & Magazines	Results Key: JNL = Journal or Magazine CNF = Conference STD = Standard
Conference Proceedings	1 A 3.6 V 4 W 0.2cc Si power-MOS-amplifier module for GSM handset phones
O- Standards	Yoshida, S.; Katsueda, M.; Morikawa, M.; Matsunaga, Y.; Fujioka, T.; Hotta, Nunogawa, Y.; Kobayashi, K.; Shimuzu, S.; Nagata, M.;
Search	Solid-State Circuits Conference, 1998. Digest of Technical Papers. 45th ISSC 1998 IEEE International, 5-7 Feb. 1998
O- By Author D- Basic	Pages:50 - 51
O- Advanced	[Abstract] [PDF Full-Text (568KB)] IEEE CNF
Member Services	
O- Join IEEE O- Establish IEEE Web Account	
Access the IEEE Member Digital Library	

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help. | FAQ| Terms | Back to Top

Copyright © 2004 IEEE - All rights reserved



Membership Public	ations/Services Stand	dards Conferences	Careers/Jobs			
IEEE /	Xplore® RELEASE 1.6	United States P	Welcome atent and Trademark Office	7 ! 7 ! 7 !		
Help FAQ Terms	IEEE Peer Review Quic	k Links		» A		
Welcome to IEEE Xplore®	To Locate an Aut	thor:				
O- Home O- What Can	 Enter a last name or select a letter in the alphabet. Once you identify the name, select it to search the database for relevant articles. 					
I Access?	1.Options:					
C Log-out Tables of Contents	» Enter a name to find	an author:	Go			
O- Journals & Magazines	Example:Enter Lockett S OR» Select a letter to bi		hors with the last name Lockett and fire	st name initial S.		
O- Conference Proceedings	ABCDEFGHI	JKLMNOPQ	RSTUVWXYZ ALL			
O- Standards	2. Select an auth	or name to sea	rch the database for releva	nt articles:		
Search	Kamijoh N.		Kamijoh T.			
O- By Author O- Basic O- Advanced	ABCDEFGHI	JKLMNOPQ	RSTUVWXYZ ALL			
Member Services			·			
O- Join IEEE O- Establish IEEE Web Account						
Access the IEEE Member Digital Library						

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ| Terms | Back to Top

Copyright © 2004 IEEE — All rights reserved